## Application/Control No. 10/672,521 Applicant(s)/Patent Under Reexamination TAKAYAMA ET AL. Examiner Ha T. Nguyen Applicant(s)/Patent Under Reexamination TAKAYAMA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,078,071 A	06-2000	Matsuda, Hajime	257/280
	В	US-6,245,668 B1	06-2001	Brodsky et al.	438/627
	С	US-4,619,695	10-1986	Oikawa et al.	75/10.65
	D	US-5,208,170 A	05-1993	Kobeda et al.	438/625
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-		,	

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-408153722-A	06-1996	Japan	Ikeda et al.	
	0					
	Р					
	Q			/		
	R					
	s					
	Т			/		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Vm 215-5